

Search Notes

Application/Control No.

09/932,810

Examiner

Blake E. Betz

Applicant(s)/Patent under
Reexamination

FUNAKUBO ET AL.

Art Unit

2672

SEARCHED

Class	Subclass	Date	Examiner
345	426 441 589 617	12/2/2004	BB
	611 612 613	1/13/2005	BB
	614 615 616	1/13/2005	BB
348	597 673	12/2/2004	BB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
("anti-aliasing" or "antialiasing") and vertex and between same scan same (distance or length)	1/21/2005	BB
("anti-aliasing" or "antialiasing" or "anti aliasing") same (polygon or triangle or line or edge) same intensity	12/3/2004	BB
scan adj2 line and (antialias\$3 or anti alias\$3) same (length or distance) same averag\$3	1/21/2005	BB
345/611.ccls. and box	1/13/2005	BB